

**Notice of References Cited**

Application/Control No.

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Applicant(s)/Patent Under

Reexamination

WEI ET AL.

Examiner

Quang Nguyen, Ph.D.

Art Unit

1636

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,825,021 B2	11-2004	Luche et al.	435/196
	B	US-			
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	D	US-			
	E	US-			
	F	US-			
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	I	US-			
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	K	US-			
	L	US-			
	M	US-			

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	N	WO 97/00315	01-1997	WIPO		
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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